Search Notes



Application/Control	No.

10/790,001 Examiner

Patrick H. Mackey

Applicant(s)/Patent under Reexamination

NAKAMURA ET AL.

Art Unit

3651

SEARCHED				
Class	Subclass	Date	Examiner	
270	58.01 59 58.08			
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399	410			
271	189	10/28/2005	РНМ	

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
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Text Search East (USPGPUB, USPAT, EPO, JPO, DERWENT), see search history printout	10/28/2005	РНМ	
Plus Search	10/28/2005	РНМ	
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